

<b>Notice of References Cited</b>	Application/Control No. 10/563,429	Applicant(s)/Patent Under Reexamination INOUE, FUJIO	
	Examiner Chen-Wen Jiang	Art Unit 3744	Page 1 of 1

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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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